

CoolSiC™ M1 CoolSiC™ MOSFET 650 V G1

The 650 V CoolSiC™ is built over the solid silicon carbide technology developed in Infineon in more than 20 years. Leveraging the wide bandgap SiC material characteristics, the 650V CoolSiC™ MOSFET offers a unique combination of performance, reliability and ease of use. Suitable for high temperature and harsh operations, it enables the simplified and cost effective deployment of the highest system efficiency.

Tab

PG-T0247-3

Features

- Optimized switching behavior at higher currents
- Commutation robust fast body diode with low Q_{fr}
- Superior gate oxide reliability
- T_{j,max}=175°C and excellent thermal behavior
- Lower $R_{DS(on)}$ and pulse current dependency on temperature
- Increased avalanche capability
- Compatible with standard drivers
- Kelvin source provides up to 4 times lower switching losses



- · Unique combination of high performance, high reliability and ease of use
- Ease of use and integration
- Suitable for topologies with continuous hard commutation
- Higher robustness and system reliability
- Efficiency improvement
- Reduced system size leading to higher power density

Potential applications

- SMPS
- UPS (uninterruptable power supplies)
- Solar PV inverters
- EV charging infrastructure
- · Energy storage and battery formation
- Class D amplifiers

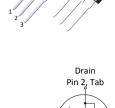
Product validation

Fully qualified according to JEDEC for Industrial Applications

Table 1 Key performance parameters

Parameter	Value	Unit
$V_{DS} @ T_J = 25 ^{\circ}\text{C}$	650	V
$R_{\mathrm{DS(on),typ}}$	48	mΩ
$R_{\mathrm{DS(on),max}}$	64	mΩ
$Q_{G,typ}$	33	nC
I _{DM,max}	100	А
Q _{oss} @ 400 V	78	nC
<i>E_{oss}</i> @ 400 V	11.7	μЈ

Part number	Package	Marking	Related links
IMW65R048M1H	PG-TO247-3	65R048M1	see Appendix A









Public

CoolSiC™ MOSFET 650 V G1

IMW65R048M1H



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1 Maximum ratings

at $T_i = 25$ °C, unless otherwise specified.

Note: for optimum lifetime and reliability, Infineon recommends operating conditions that do not exceed 80% of the maximum ratings stated in this datasheet.

Table 2 Maximum ratings

Davamatav	Cymphol	Values			l lmit	Note / Test condition	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test condition	
Continuous DC drain current 1)	I_{DDC}	-	-	40 28	А	$T_c = 25 ^{\circ}\text{C}$ $T_c = 100 ^{\circ}\text{C}$	
Peak drain current ²⁾	I _{DM}	-	-	100	А	$T_{\rm c}$ = 25 °C, $V_{\rm GS}$ = 18 V	
Avalanche energy, single pulse	E _{AS}	-	-	171	mJ	/ = 6 / A // = 50 //: soo table 11	
Avalanche energy, repetitive	E_{AR}	-	-	0.85	mJ	I _D = 6.4 A, V _{DD} = 50 V; see table 11	
Avalanche current, single pulse	I _{AS}	-	-	6.4	А	-	
MOSFET <i>dv/dt</i> ruggedness	dv/dt	-	-	200	V/ns	V _{DS} = 0400 V	
Gate source voltage (static) 3)	V_{GS}	-5	-	23	V	-	
Gate source voltage (transient)	$V_{\rm GS}$	-7	-	25	V	t _{pulse} ≤ 1% duty cycle/f _{sw}	
Power dissipation	P_{tot}	-	-	150	W	T _c = 25 °C	
Storage temperature	$T_{\rm stg}$	-55	-	150	°C		
Operating junction temperature	$T_{\rm j}$	-55	-	175	°C	-	
Mounting torque	-	-	-	60	Ncm	M3 and M3.5 screws	
Continuous reverse drain current 1)	I _{SDC}	-	-	40 26	А	$V_{\rm GS} = 18 \text{ V}, T_{\rm c} = 25 ^{\circ}\text{C}$ $V_{\rm GS} = 0 \text{ V}, T_{\rm c} = 25 ^{\circ}\text{C}$	
Peak reverse drain current ²⁾	I _{SM}	-	-	100	Α	$T_{\rm c} = 25 {\rm ^{\circ}C}, t_{\rm p} \le 250 {\rm ns}$	
Insulation withstand voltage	V _{ISO}	-	-	n.a.	٧	$V_{\rm rms}$, $T_{\rm c} = 25$ °C, $t = 1$ min	

 $^{^{1)}}$ Limited by $T_{\rm j,max}$

²⁾ Pulse width t_{pulse} limited by $T_{\text{j,max}}$.

³⁾ The maximum gate-source voltage in the application design should be in accordance to IPC-9592B.



2 Thermal characteristics

Table 3 Thermal characteristics

Parameter	Symbol	Values			Linit	Note / Test condition
raiailietei	Symbol	Min.	Тур.	Max.	Onic	Note / Test condition
Thermal resistance, junction - case	$R_{th(j-c)}$	-	-	1.0	°C/W	-
Thermal resistance, junction - ambient	R _{th(j-a)}		-	62	°C/W	Leaded
Thermal resistance, junction - ambient, SMD version	$R_{th(j-a)}$	h(j-a)		-	°C/W	n.a.
Soldering temperature, wavesoldering only allowed at leads	$T_{\rm sold}$	-	-	260	°C	1.6mm (0.063 in.) from case for 10s



3 Operating range

Table 4 Operating range

Parameter	Symbol	Values			Limit	Note / Test condition
Parameter	Syllibot	Min.	Тур.	Max.	Unit	Note / Test condition
Gate-source voltage operating range including undershoots ⁴⁾	V_{GS}	-2	-	20	V	
Recommended turn-on voltage	$V_{\rm GS(on)}$	-	18	-	V	-
Recommended turn-off voltage	$V_{\rm GS(off)}$	-	0	-	V	

4)

Important notice: If the gate source voltage of the device in application exceeds the operating range (Table 4), the device RDS,on and VGS(th) might exceed the maximum value stated in the datasheet at the end of the lifetime of the device. In order to ensure sound operation of the device over the planned lifetime, the maximum ratings (Table 2) and the CoolSiC TM MOSFET 650V M1 trench power device application note AN_1907_PL52_1911_144109 must be considered.



4 Electrical characteristics

at $T_i = 25$ °C, unless otherwise specified

Table 5 Static characteristics

Parameter	Symbol	Values			Linit	Note / Test condition
Parameter	Symbol	Min.	Тур.	Max.	Onic	Note / Test condition
Drain-source voltage	$V_{\rm DSS}$	650	-	-	V	$V_{\rm GS} = 0 \text{V}, I_{\rm D} = 0.6 \text{mA}$
Gate threshold voltage ⁵⁾	$V_{\rm GS(th)}$	3.5	4.5	5.7	V	$V_{\rm DS} = V_{\rm GS}$, $I_{\rm D} = 6$ mA
Zero gate voltage drain current	I _{DSS}	-	1 3	100		$V_{\rm DS} = 650 \text{ V}, V_{\rm GS} = 0 \text{ V}, T_{\rm j} = 25 \text{ °C}$ $V_{\rm DS} = 650 \text{ V}, V_{\rm GS} = 0 \text{ V}, T_{\rm j} = 175 \text{ °C}$
Gate-source leakage current	I _{GSS}	-	-	100	nA	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$
Drain-source on-state resistance	R _{DS(on)}	_	48 67	64 -	mΩ	$V_{GS} = 18 \text{ V}, I_D = 20.1 \text{ A}, T_j = 25 \text{ °C}$ $V_{GS} = 18 \text{ V}, I_D = 20.1 \text{ A}, T_j = 175 \text{ °C}$
Internal gate resistance	$R_{G,int}$	-	6.0	-	Ω	f= 1 MHz

⁵⁾ Tested after 1 ms pulse at V_{GS} = +20 V

Table 6 Dynamic characteristics

Parameter	Cymphal	Values			1100:4	Note / Took oom diki om
	Symbol	Min.	Тур.	Max.	Jonic	Note / Test condition
Input capacitance	C _{iss}	-	1118	-	pF	
Reverse transfer capacitance	C _{rss}	-	13	-	pF	$V_{GS} = 0 \text{ V}, V_{DS} = 400 \text{ V}, f = 250 \text{ kHz}$
Output capacitance ⁶⁾	C _{oss}	-	129	168	pF	
Output charge ⁶⁾	$Q_{\rm oss}$	-	78	101	nC	calculation based on C _{oss}
Effective output capacitance, energy related ⁷⁾	$C_{ m o(er)}$	-	146	-	pF	$V_{GS} = 0 \text{ V},$ $V_{DS} = 0400 \text{ V}$
Effective output capacitance, time related ⁸⁾	$C_{\rm o(tr)}$	-	194	-	pF	$I_{\rm D}$ = constant, $V_{\rm GS}$ = 0 V, $V_{\rm DS}$ = 0 400 V
Turn-on delay time	t _{d(on)}	-	14.6	-	ns	
Rise time	t _r	-	12.4	-	ns	$V_{\rm DD} = 400 \text{ V}, V_{\rm GS} = 0/18 \text{ V}, \ I_{\rm D} = 20.1 \text{ A}, R_{\rm G,ext} = 1.8 \Omega; \ m see table 10$
Turn-off delay time	$t_{\sf d(off)}$	-	15.4	-	ns	
Fall time	t _f		11.4	-	ns	

⁶⁾ Maximum specification is defined by calculated six sigma upper confidence bound

⁷⁾ $C_{o(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 400 V.

⁸⁾ $C_{\rm o(tr)}$ is a fixed capacitance that gives the same charging time as $C_{\rm oss}$ while $V_{\rm DS}$ is rising from 0 to 400 V.



Table 7 Gate charge characteristics

Darameter	Symbol	Values			Linit	Note / Test condition
Parameter	Symbol	Min.	Тур.	Max.	Onit	Note / Test condition
Plateau gate to source charge	$Q_{GS(pl)}$	-	9	-	nC	V 400 V / 20 1 A
Gate to drain charge	Q_{GD}	-	8	-	nC	$V_{\rm DD} = 400 \text{V}, I_{\rm D} = 20.1 \text{A},$ $V_{\rm GS} = 0 \text{to} 18 \text{V}$
Total gate charge	Q_{G}	-	33	-	nC	V _{GS} 0 to 13 v

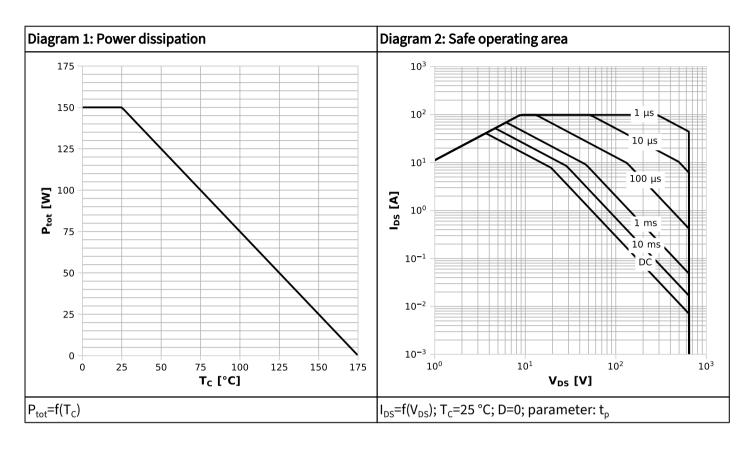
Table 8 Reverse diode characteristics

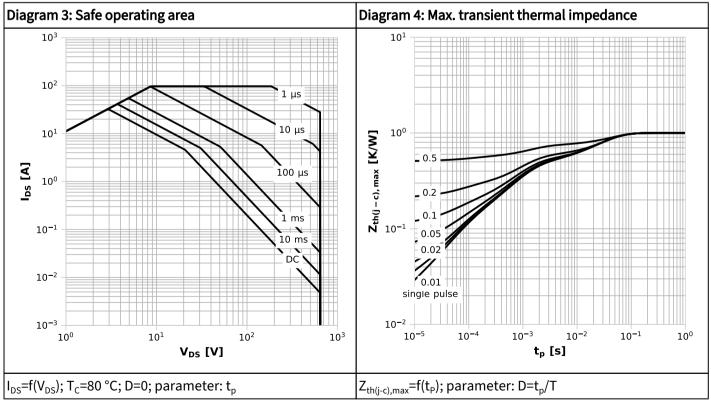
Parameter	Symbol	Values			Linit	Note / Test condition
rarameter	Syllibol	Min.	Тур.	Max.	Oilit	Note / Test condition
Drain-source reverse voltage	$V_{\rm SD}$	-	4.0	-	V	$V_{GS} = 0 \text{ V}, I_{S} = 20.1 \text{ A}, T_{j} = 25 \text{ °C}$
MOSFET forward recovery time	t_{fr}	-	68	-	ns	
MOSFET forward recovery charge ⁹⁾	Q_{fr}	-	125	-		$V_{\rm DD} = 400 \text{V}, I_{\rm S} = 20.1 \text{A},$
MOSFET peak forward recovery current	I _{frm}	-	8.4	-	А	$di_s/dt = 1000 A/\mu s$; see table 9

⁹⁾ $Q_{\rm fr}$ includes $Q_{\rm oss}$

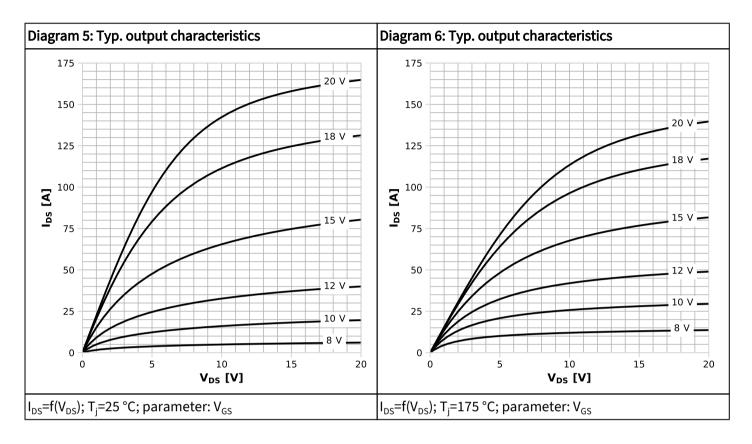


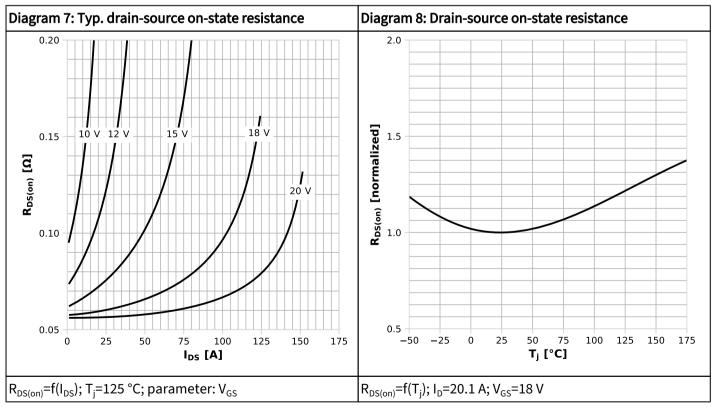
5 Electrical characteristics diagrams



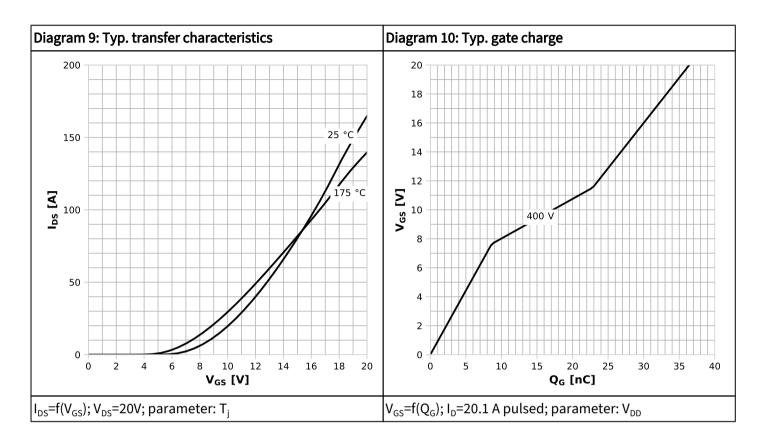


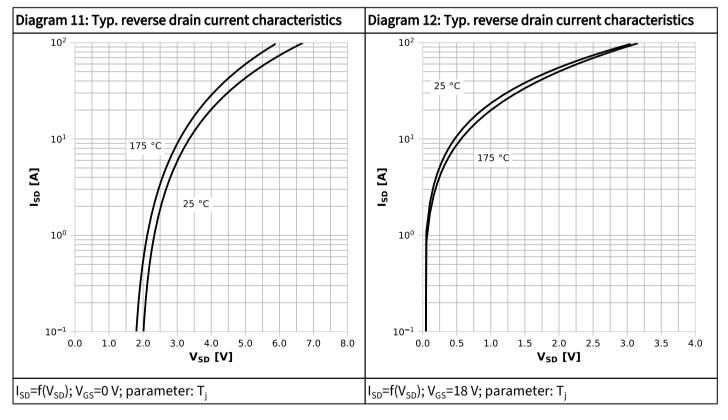




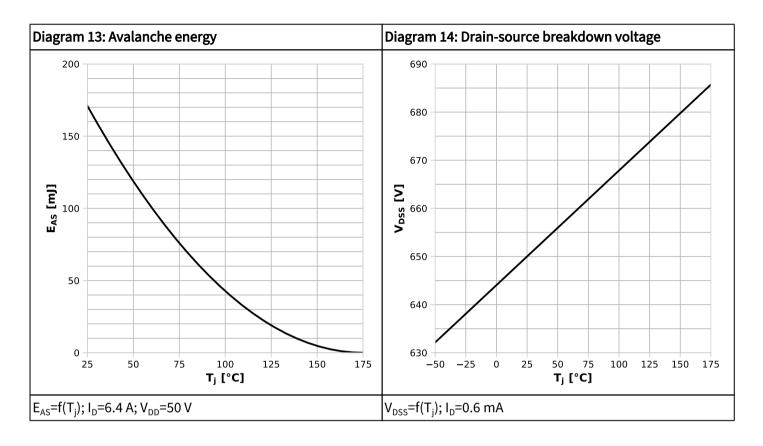


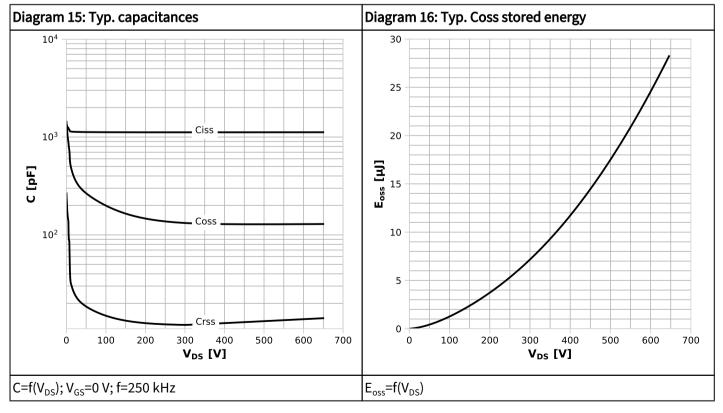




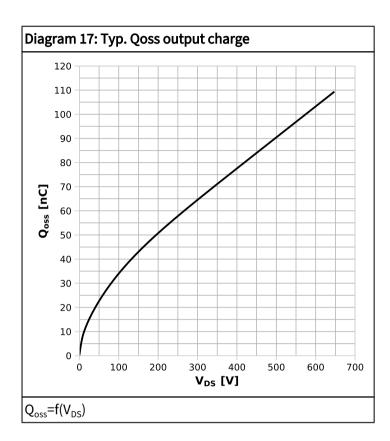














6 Test circuits

Table 9 Body diode characteristics

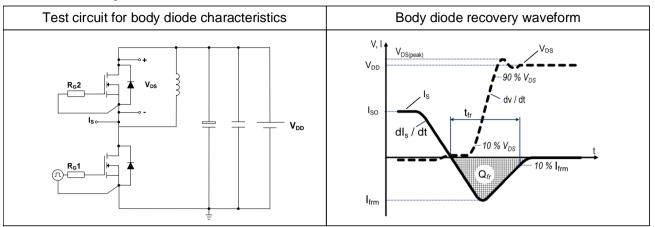


Table 10 Switching times

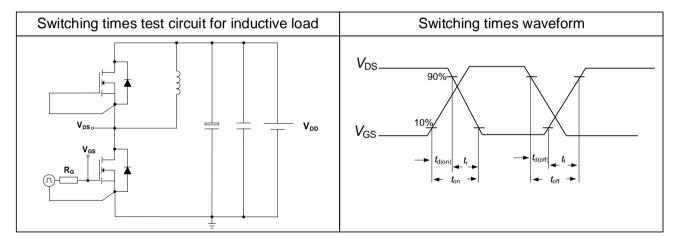
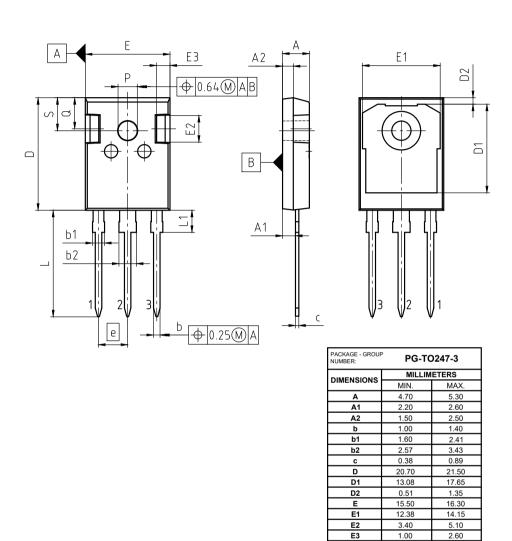


Table 11 Unclamped inductive load





7 Package outlines



DIMENSIONS DO NOT INCLUDE MOLDFLASH; PROTRUSION OR GATE BURRS

Figure 1 Outline PG-TO247-3, dimensions in mm

N

L1 øP

Q

19.80

3.85 3.50 20.40

3.70

6.30



8 Appendix A

Table 12 Related links

- IFX CoolSiC CoolSiC™ MOSFET 650 V G1 Webpage
- IFX CoolSiC CoolSiC™ MOSFET 650 V G1 Application Note
- IFX CoolSiC CoolSiC™ MOSFET 650 V G1 Simulation Model
- IFX Design tools

CoolSiC™ MOSFET 650 V G1



Revision history

IMW65R048M1H

Revision 2025-01-20, Rev. 2.3

Previous revisions

Revision	Date	Subjects (major changes since last revision)
2.0	2019-12-16	Release of final version
2.1	2022-04-01	Updated Vgs specs
2.2	2024-08-26	$V_{\rm GS}$ specs update , $T_{\rm j,max}$ update , $I_{\rm DSS}$ update, nomenclature update, datasheet layout update.
2.3	2025-01-20	Corrected Is value in test condition of parameter Vsd.

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